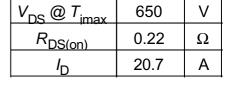


#### **Cool MOS™ Power Transistor**

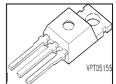
#### **Feature**

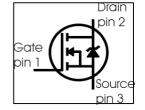
- New revolutionary high voltage technology
- Worldwide best R<sub>DS(on)</sub> in TO 220
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- High peak current capability
- Intrinsic fast-recovery body diode
- Extreme low reverse recovery charge
- Pb-free lead plating; RoHS compliant; Halogen free mold compound
- Qualified for industrial grade applications according to JEDEC<sup>0)</sup>

Туре	Package	Ordering Code	Marking
SPP20N60CFD	PG-TO220	Q67040-S4616	20N60CFD









### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Continuous drain current	I <sub>D</sub>		А
$T_{\rm C}$ = 25 °C		20.7	
T <sub>C</sub> = 100 °C		13.1	
Pulsed drain current, $t_p$ limited by $T_{imax}$	I <sub>D puls</sub>	52	
Avalanche energy, single pulse	E <sub>AS</sub>	690	mJ
$I_{\rm D} = 10 \text{ A}, \ V_{\rm DD} = 50 \text{ V}$			
Avalanche energy, repetitive $t_{AR}$ limited by $T_{jmax}$ 1)	E <sub>AR</sub>	1	
$I_{\rm D} = 20 \text{ A}, V_{\rm DD} = 50 \text{ V}$			
Avalanche current, repetitive $t_{AR}$ limited by $T_{imax}$	I <sub>AR</sub>	20	Α
Reverse diode d <i>v</i> /d <i>t</i>	d <i>v</i> /d <i>t</i>	40	V/ns
I <sub>S</sub> =20.7A, V <sub>DS</sub> =480V, T <sub>i</sub> =125°C			
Gate source voltage	$V_{GS}$	±20	V
Gate source voltage AC (f >1Hz)	$V_{\rm GS}$	±30	
Power dissipation, T <sub>C</sub> = 25°C	P <sub>tot</sub>	208	W
Operating and storage temperature	T <sub>i</sub> , T <sub>sta</sub>	-55 +150	°C



**Maximum Ratings** 

Parameter	Symbol	Value	Unit
Drain Source voltage slope	d <i>v</i> /d <i>t</i>	80	V/ns
$V_{\rm DS}$ = 480 V, $I_{\rm D}$ = 20.7 A, $T_{\rm j}$ = 125 °C			
Maximum diode commutation speed	d <i>i </i> dt	900	A/µs
$V_{\rm DS}$ = 480 V, $I_{\rm D}$ = 20.7 A, $T_{\rm j}$ = 125 °C			

#### **Thermal Characteristics**

Parameter	Symbol	nbol Value			Unit
		min.	typ.	max.	<u> </u>
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$	-	-	0.6	K/W
Thermal resistance, junction - ambient, leaded	R <sub>thJA</sub>	-	-	62	
Soldering temperature, wavesoldering	T <sub>sold</sub>	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s	00.0				

## Electrical Characteristics, at Tj=25°C unless otherwise specified

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =0.25mA	600	-	-	V
Drain-Source avalanche	V <sub>(BR)DS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =20A	-	700	-	
breakdown voltage						
Gate threshold voltage	V <sub>GS(th)</sub>	/ <sub>D</sub> =1000μA, V <sub>GS</sub> =V <sub>DS</sub>	3	4	5	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V,				μΑ
		<i>T</i> <sub>j</sub> =25°C,	-	2.1	-	
		<i>T</i> <sub>j</sub> =150°C	-	1700	-	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	1	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	VGS=10V, ID=13.1A,				Ω
		<i>T</i> <sub>j</sub> =25°C	-	0.19	0.22	
		<i>T</i> <sub>j</sub> =150°C	-	0.51	-	
Gate input resistance	$R_{G}$	f=1MHz, open Drain	-	0.54	-	



**Electrical Characteristics**, at  $T_i$  = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Transconductance	$g_{fs}$	$V_{DS} \ge 2*I_D*R_{DS(on)max}$ $I_D = 13.1A$	ı	17.5	-	S
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V,	-	2400	-	pF
Output capacitance	Coss	f=1MHz	-	780	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	50	-	
Effective output capacitance, <sup>2)</sup> energy related	C <sub>o(er)</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V to 480V	-	83	-	pF
Effective output capacitance, <sup>3)</sup> time related	C <sub>o(tr)</sub>		-	160	-	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =380V, V <sub>GS</sub> =0/10V,	-	12	-	ns
Rise time	$t_{r}$	$I_{\rm D}$ =20.7A, $R_{\rm G}$ =3.6 $\Omega$	-	15	-	
Turn-off delay time	t <sub>d(off)</sub>		-	59	-	
Fall time	$t_{f}$		-	6.4	-	

#### **Gate Charge Characteristics**

Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =480V, I <sub>D</sub> =20.7A	-	15	-	nC
Gate to drain charge	$Q_{ad}$		-	54	-	
Gate charge total	$Q_{g}$	V <sub>DD</sub> =480V, I <sub>D</sub> =20.7A,	-	95	124	
		V <sub>GS</sub> =0 to 10V				
Gate plateau voltage	V <sub>(plateau)</sub>	V <sub>DD</sub> =480V, I <sub>D</sub> =20.7A	-	7	-	V

<sup>&</sup>lt;sup>0</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>1</sup>Repetitve avalanche causes additional power losses that can be calculated as  $P_{AV} = E_{AR} * f$ .

 $<sup>^2</sup>C_{
m o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{
m oss}$  while  $V_{
m DS}$  is rising from 0 to 80%  $V_{
m DSS}$ .

 $<sup>^3</sup>C_{\rm o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 80%  $V_{\rm DSS}$ .

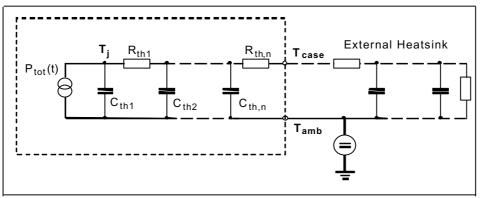


**Electrical Characteristics**, at  $T_i$  = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Inverse diode continuous forward current	Is	T <sub>C</sub> =25°C	-	-	20.7	A
Inverse diode direct current, pulsed	I <sub>SM</sub>		-	-	52	
Inverse diode forward voltage	$V_{SD}$	V <sub>GS</sub> =0V, I <sub>F</sub> =I <sub>S</sub>	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =480V, I <sub>F</sub> =I <sub>S</sub> ,	-	150	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100A/µs	-	1	-	μC
Peak reverse recovery current	I <sub>rrm</sub>		_	13	-	Α
Peak rate of fall of reverse recovery current	di /dt		-	1400	-	A/µs

**Typical Transient Thermal Characteristics** 

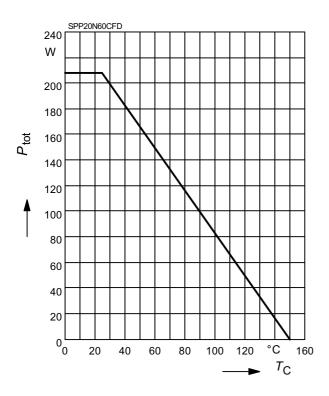
Symbol	Value	Unit	Symbol	Value	Unit
	typ.			typ.	
Thermal re	esistance	·	Thermal c	apacitance	·
R <sub>th1</sub>	0.007686	K/W	C <sub>th1</sub>	0.0003764	Ws/K
R <sub>th2</sub>	0.015		C <sub>th2</sub>	0.001412	
R <sub>th3</sub>	0.029		C <sub>th3</sub>	0.001932	
R <sub>th4</sub>	0.114		C <sub>th4</sub>	0.005299	
$R_{th5}$	0.136		C <sub>th5</sub>	0.012	
R <sub>th6</sub>	0.059		C <sub>th6</sub>	0.091	





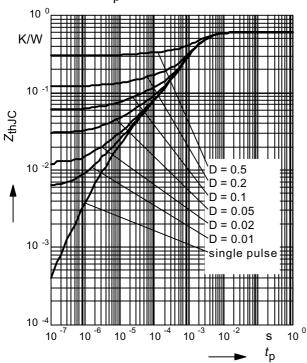
#### 1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}})$$



#### 3 Transient thermal impedance

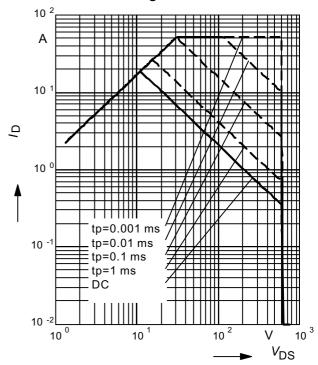
$$Z_{\text{thJC}} = f(t_{\text{p}})$$
  
parameter:  $D = t_{\text{p}}/T$ 



#### 2 Safe operating area

$$I_{\rm D} = f(V_{\rm DS})$$

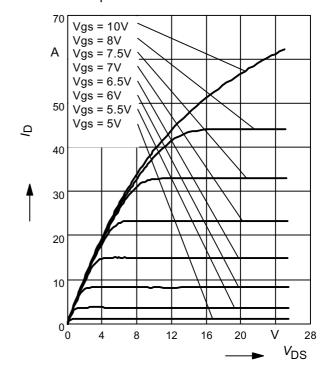
parameter : D = 0 ,  $T_C = 25$ °C



#### 4 Typ. output characteristic

$$I_{D} = f(V_{DS}); T_{j} = 25^{\circ}C$$

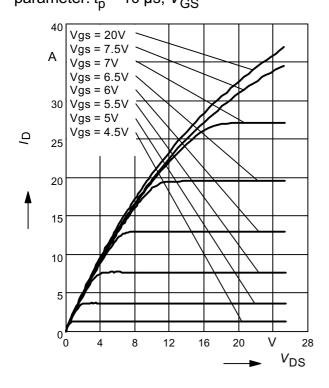
parameter:  $t_p$  = 10  $\mu$ s,  $V_{GS}$ 





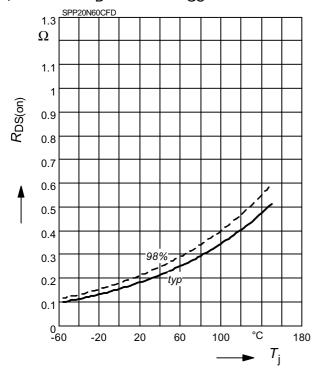
### 5 Typ. output characteristic

 $I_{\rm D}$  =  $f(V_{\rm DS})$ ;  $T_{\rm j}$ =150°C parameter:  $t_{\rm p}$  = 10 µs,  $V_{\rm GS}$ 



#### 7 Drain-source on-state resistance

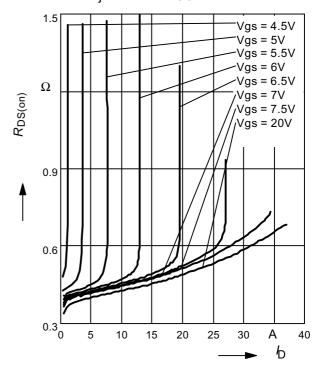
 $R_{DS(on)} = f(T_j)$ parameter :  $I_D = 13.1 \text{ A}, V_{GS} = 10 \text{ V}$ 



#### 6 Typ. drain-source on resistance

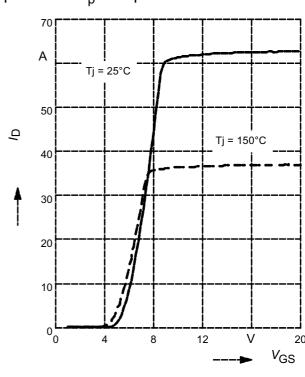
 $R_{DS(on)} = f(I_D)$ 

parameter:  $T_i$ =150°C,  $V_{GS}$ 



#### 8 Typ. transfer characteristics

 $I_{\rm D}$ =  $f(V_{\rm GS})$ ;  $V_{\rm DS}$  $\geq 2 \times I_{\rm D} \times R_{\rm DS(on)max}$ parameter:  $t_{\rm p}$  = 10  $\mu$ s

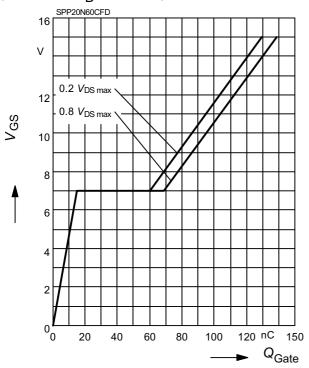




#### 9 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$ 

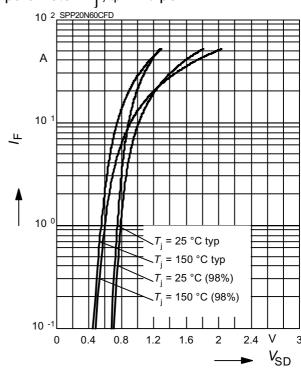
parameter:  $I_D = 20.7 \text{ A pulsed}$ 



#### 10 Forward characteristics of body diode

 $I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$ 

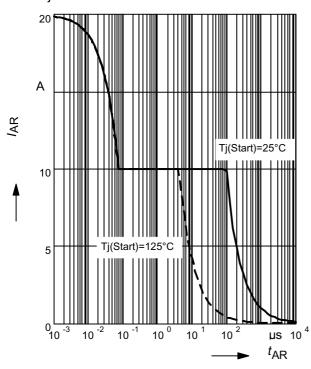
parameter:  $T_i$ ,  $t_p = 10 \mu s$ 



#### 11 Avalanche SOA

 $I_{AR} = f(t_{AR})$ 

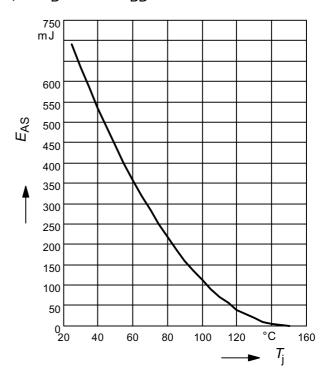
par.:  $T_j \le 150 \, ^{\circ}\text{C}$ 



### 12 Avalanche energy

 $E_{AS} = f(T_i)$ 

par.:  $I_D = 10 \text{ A}, V_{DD} = 50 \text{ V}$ 

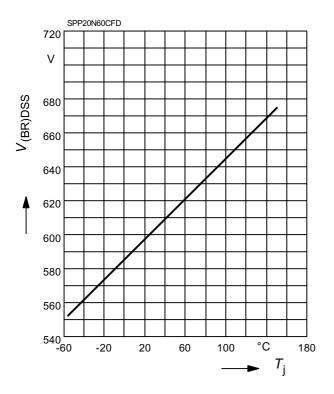






## 13 Drain-source breakdown voltage

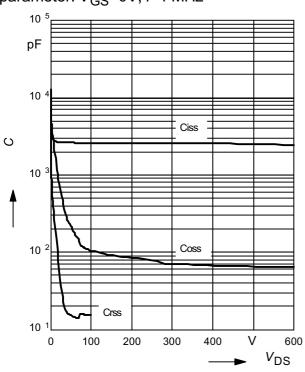
$$V_{(BR)DSS} = f(T_j)$$



## 15 Typ. capacitances

$$C = f(V_{DS})$$

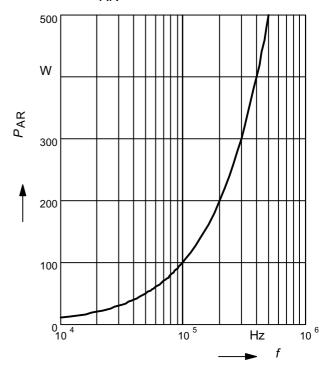
parameter: V<sub>GS</sub>=0V, f=1 MHz



### 14 Avalanche power losses

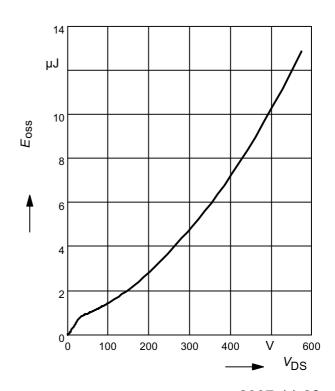
$$P_{AR} = f(f)$$

parameter: E<sub>AR</sub>=1mJ



# 16 Typ. $C_{\rm oss}$ stored energy

$$E_{\rm oss} = f(V_{\rm DS})$$



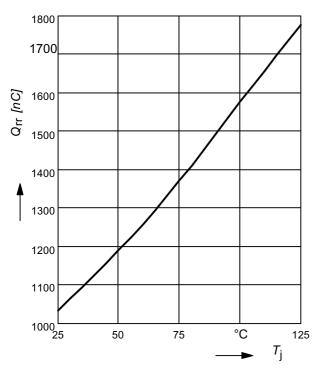




## 17 Typ. reverse recovery charge

$$Q_{rr} = f(T_J)$$

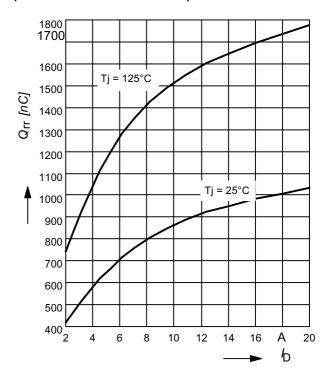
parameter:  $I_D = 20.7A$ 



## 18 Typ. reverse recovery charge

$$Q_{rr} = f(I_D)$$

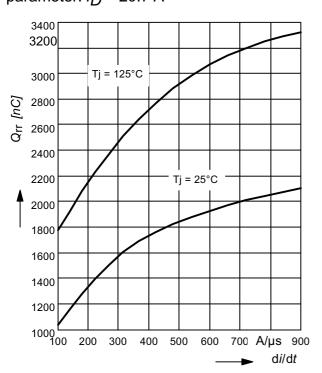
parameter: di/dt = 100 A/μs



### 19 Typ. reverse recovery charge

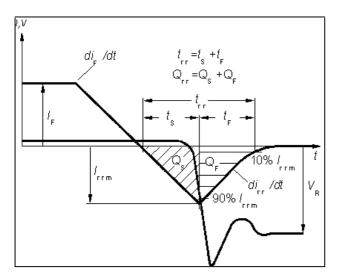
$$Q_{rr} = f(di/dt)$$

parameter:  $I_D = 20.7 \text{ A}$ 



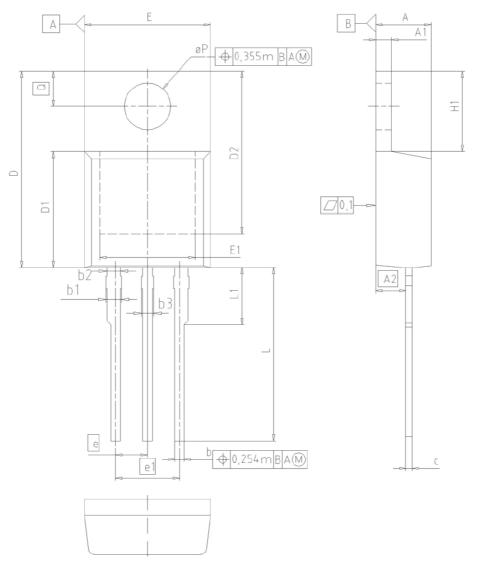


## Definition of diodes switching characteristics

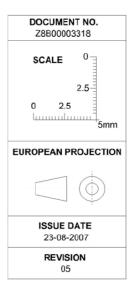




#### PG-TO-220-3-1, PG-TO220-3-21



DIM	MILLI	METERS	INC	HES
DIN	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
С	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
е	2	.54	0.	100
e1	5	.08	0.:	200
N		3		3
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øΡ	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118







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